

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination FUJIOKA ET AL.	
			10/812,185	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,740,975	04-1988	Abrahams et al.	372/41
*	B	US-5,119,389	06-1992	Amano, Sho	372/23
*	C	US-5,436,919	07-1995	Chwalek et al.	372/7
*	D	US-6,160,824	12-2000	Meissner et al.	372/7
*	E	US-6,700,906	03-2004	Hackel et al.	372/22
*	F	US-6,879,604	04-2005	Cook, Gary	372/3
*	G	US-6,914,928	07-2005	Trussell, Jr., C. Ward	372/71
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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